PERICOM [®]	SaRonix-eCera
PSE Technolog	y Corporation

SPECIFICATION FOR APPROVAL

CUSTOMER

NOMINAL FREQUENCY

32.768 KHz

TYPE G9 SMD CRYSTAL

PRODUCT TYPE

SPEC. NO. (P/N)

CUSTOMER P/N

ISSUE DATE

VERSION

G93270001

Jan.8,2014

С

APPROVED	PREPARED	QA
Brenda	Claire	Bedayiri
APPROVED BY	CUSTOMER :	AVL Status
Please return one copy	with approval to PSE-TW	

PSE Technology Corporation

No.2, Tzu-Chiang 5th Rd, Chung Li Industrial Park, Chung Li City, Taoyuan County, Taiwan (R.O.C.) TEL: 886-3-451-8888 FAX: 886-3-461-3865 http://www.saronix-ecera.com.tw *Pb-free

*RoHS Compliant

*HF-Halogen Free

*REACH Compliant

*** A company of 💋 PERICOM Semiconductor Corporation ***

G93270001

VER. C 3-Oct-11

VERSION HISTORY

Version No.	Version Date	Customer Receipt Date	Supplier Receipt Date	Description	Notes
А	Apr.18,2011			Initial Release	
В	Oct.3,2011			Changed Operating Temperature Range from -30~70C to -40~85C & Added Shunt Capacitance 7pF	
С	Jan.8,2014			Revised to RoHS Compliant	



G93270001

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ELECTRICAL SPECIFICATIONS

SRe Part Number: G93270001

Parameters	Symbol	Specifications	Units	Notes
Nominal Frequency	Fn	32.768	KHz	
Frequency Tolerance	FT	± 20	ppm	at 25°C ± 5°C
Load Capacitance	CL	9	pF	Тур.
Drive Level	DL	0.1 / 0.5	μW	Typ / Max.
Equivalent Series Resistance	ESR	90	KΩ	Max.
Temperature Coefficient	К	-0.03	ppm/°C ²	Тур.
Operating Temperature Range	TR	-40~85	°C	
Shunt Capacitance	C0	7	pF	Max.
Storage Temperature Range		-55~125	°C	
Aging		± 3	ppm	Max 1st year
Insulation Resistance		500	MΩ	Min.

Reliability (Mechanical and environmental performances)

No.	Test Items	Conditions	Requirements		
1	Bending test	Apply pressure in the direction of the arrow at a rate of about 0.5mm/s until bent width reaches 5mm, and hold for 30 seconds.	 Without mechanical damage such as breaks and satisfy sealing specification. Frequency change: Within ±5ppm 		
2	Shear test	A static load of 20N(2.04kgf) using a R0.5 scratch tool, shall be applied on the core of the component and in the direction of the arrow and held for 5 seconds.	• Equivalent series resistance(E.S.R) change: Within 5kΩ		
3	Core body strength	A static load of 10N(1.02kgf) using a R0.5 pressure rod shall be applied to the center in the direction of the arrow and held for 10 seconds.			
4	Vibration	Endurance conditioning by a frequency sweep shall be made. The entire frequency range, from 10Hz to 55Hz and return to 10Hz, shall be transversed in 1 minute. Amplitude (total excursion) : 1.5mm, This motion shall be applied for a period of 2 hours in each of 3 mutually perpendicular axes (a total of 6 hours). For other procedures, refer to JIS C 60068-2-6.			
5	Shock	Peak acceleration : 9810m/s2 · Duration of the pulse : 1ms, Three successive shock shall be applied 3 times perpendicular axes. For other procedures, refer to JIS C 60068-2-27.			

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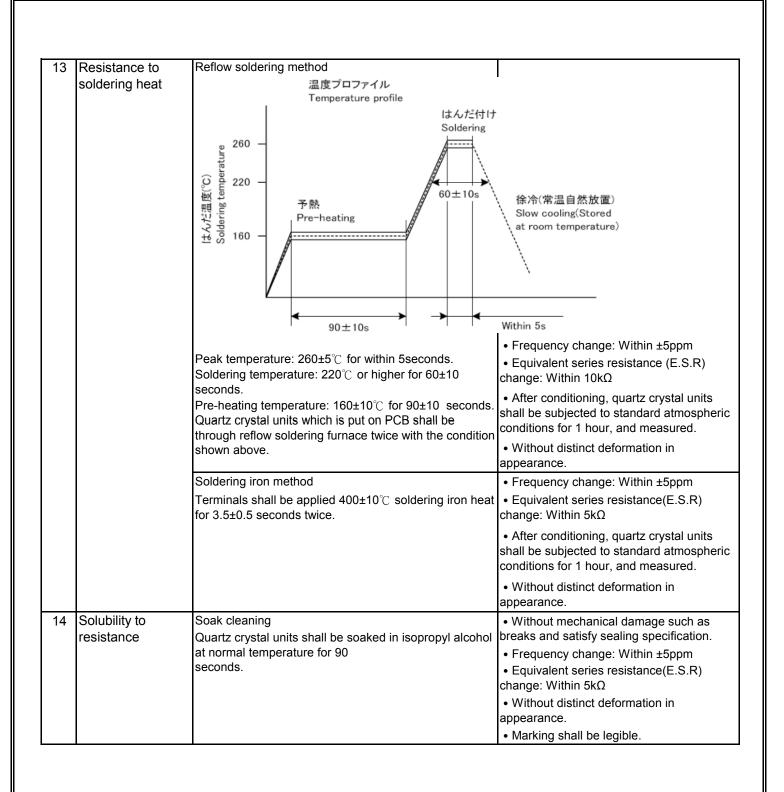
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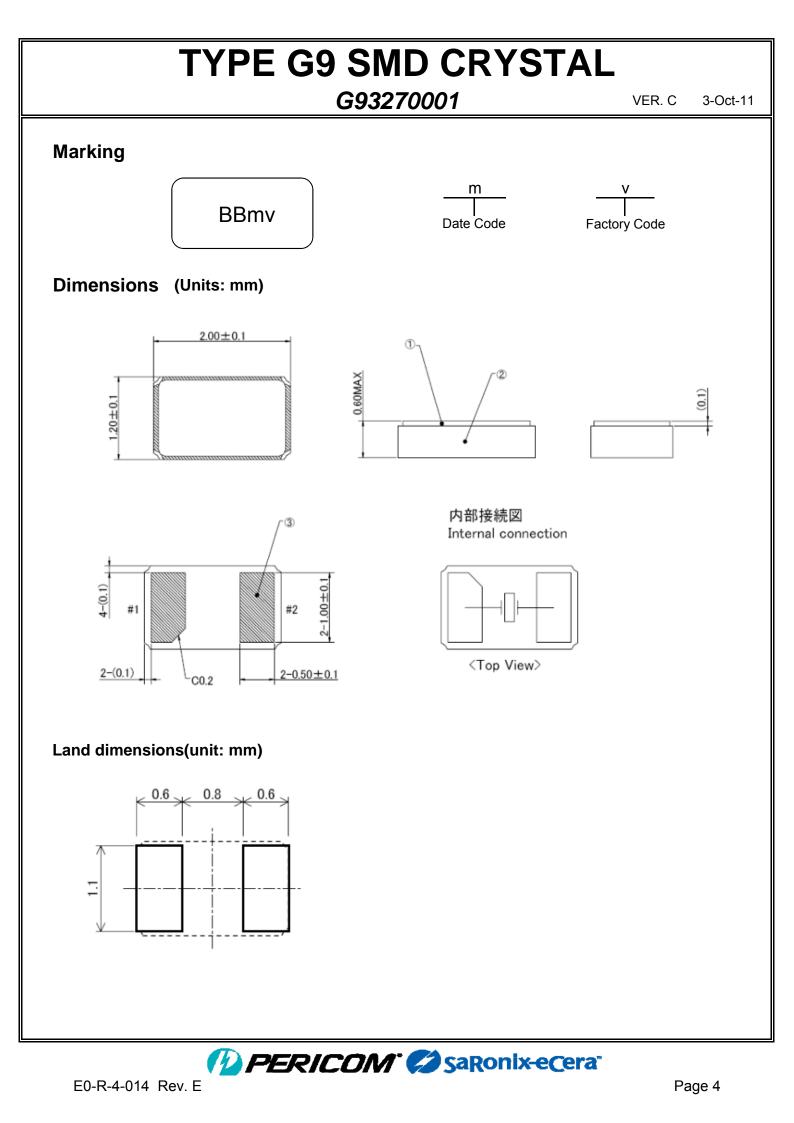
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6	Cold	Quartz crystal units shall be stored in the -40 \pm 3 $^{\circ}$ C atmosphere for 1000 hours. Other procedures conform to JIS C 60068-2-1.				 Frequency change: Within ±5ppm Equivalent series resistance(E.S.R) change: Within 5kΩ
7	Dry heat	Quartz crystal units shall be stored in the 100±2°C atmosphere for 100 hours. Other procedures conform to JIS C 60068-2-2.				• After conditioning, quartz crystal units shall be subjected to standard atmospheric conditions for 1 hour, and measured.
8	Damp heat	atmosphe	rstal units shall re with 90 to 95 ner procedures	% relati		
9	9 Change of Quartz crystal units shall be subjected successively 100 cycles of temperature change shown below. Other procedures conform to JIS C 0025.					
		1 2 3 4	Temperat -40±3℃ Normal tempe 100±2℃ Normal tempe	rature	Duration 30min. Within 30 sec. 30min. Within 30 sec.	
10	Sealing	Both the test methods specified below shall be applied. Quartz crystal units shall be soaked in 90°C or higher temperature hot water for 5 minutes. Quartz crystal units shall be tested by Mass			 Without repetitive leaking bubbles from quartz crystal units. 1×10-9 Pa · m3/s or less 	
		spectrome rate of hel	etric leakage de ium gas.	tector to		
11	Aging	Quartz crystal units shall be stored in the $85\pm3^\circ$ C atmosphere for 720 \pm 12 hours.			 Frequency change: Within ±5ppm Equivalent series resistance(E.S.R) change: Within 5kΩ 	
					• After conditioning, quartz crystal units shall be subjected to standard atmospheric conditions for 1 hour, and measured.	
12	Solder-ability		coated with flux h for 3.5±0.5 se		Minimum 95% of immersed terminal shall be covered with new uniform solder.	
			Items		Conditions	
		1	Solder	Sn-3	.0Ag-0.5Cu	
			Flux	Appr meth	oximately 25wt% anol(JIS K 8891) ion of resin(JIS K	
			Solder	255±	-0	

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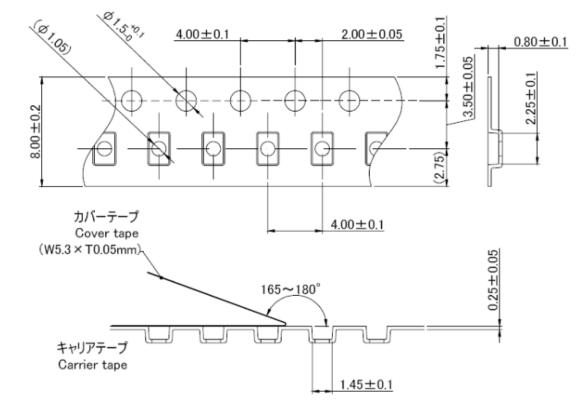




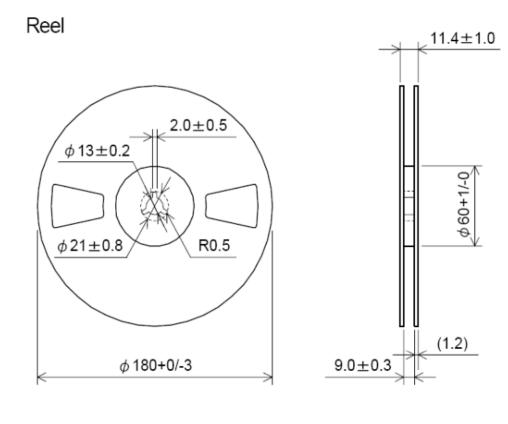
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TAPING



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E0-R-4-014 Rev. E

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